# PH2520U

# N-channel TrenchMOS ultra low level FET

Rev. 03 — 2 March 2009

**Product data sheet** 

## 1. Product profile

## 1.1 General description

Ultra low level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

## 1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Interfaces directly with low voltage gate drivers
- Low conduction losses due to low on-state resistance

## 1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Portable equipment
- Switched-mode power supplies

### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	20	V
I <sub>D</sub>	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 4.5 \text{V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	100	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 10 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 11</u> ; see <u>Figure 12</u>	-	18	-	nC
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{see } \frac{\text{Figure 10}}{\text{ or } 10}}$	-	2.1	2.7	mΩ



## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		G
4	G	gate	Qj	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH2520U	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	20	V
$V_{DGR}$	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	20	V
$V_{GS}$	gate-source voltage		-10	10	V
$I_D$	drain current	V <sub>GS</sub> = 4.5 V; T <sub>mb</sub> = 100 °C; see <u>Figure 1</u>	-	73	Α
		$V_{GS} = 4.5 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 3}};$ see Figure 3	-	100	Α
I <sub>DM</sub>	peak drain current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$ ; see Figure 3	-	300	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	62.5	W
T <sub>stg</sub>	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	52	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	150	Α
Avalanche	ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j}$ = 25 °C; $I_{D}$ = 70.7 A; $R_{GS}$ = 50 $\Omega$ ; $V_{sup} \le$ 20 V; $t_{p}$ = 0.1 ms; unclamped	-	250	mJ

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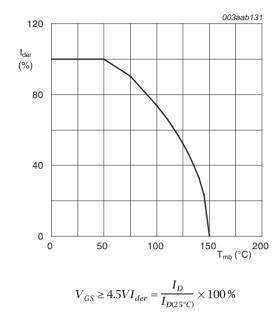


Fig 1. Normalized continuous drain current as a function of mounting base temperature

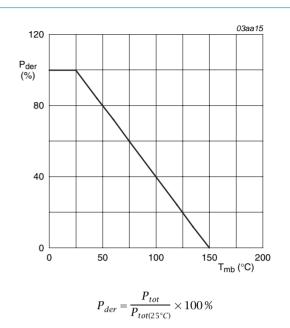
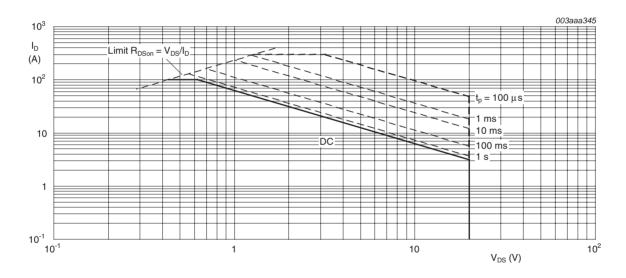


Fig 2. Normalized total power dissipation as a function of mounting base temperature

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 $T_{mb} = 25$ °C;  $I_{DM}$  is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W

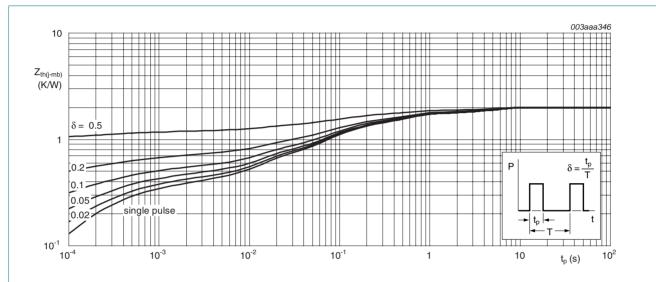


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

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## 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	18	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	20	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	1.2	V
		$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 150 \text{ °C}$ ; see Figure 7; see Figure 8	0.25	-	-	V
		$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = 25 \text{ °C}$ ; see Figure 7; see Figure 8	0.45	0.7	0.95	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.06	1	μA
		V <sub>DS</sub> = 20 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	500	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	20	100	nA
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	20	100	nA
Doon	drain-source on-state resistance	$V_{GS} = 2.5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; $T_j = 25 \text{ °C}$ ; see Figure 9; see Figure 10	-	2.8	3.9	mΩ
		$V_{GS} = 4.5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; $T_j = 150 \text{ °C}$ ; see Figure 9; see Figure 10	-	3.3	4.3	mΩ
		$V_{GS} = 4.5 \text{ V}$ ; $I_D = 25 \text{ A}$ ; $T_j = 25 \text{ °C}$ ; see Figure 9; see Figure 10	-	2.1	2.7	mΩ
$R_G$	internal gate resistance (AC)	f = 1 MHz; T <sub>j</sub> = 25 °C	-	1.65	-	Ω
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 50 \text{ A}; V_{DS} = 10 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	78	-	nC
Q <sub>GS</sub>	gate-source charge	T <sub>j</sub> = 25 °C; see <u>Figure 11</u> ;	-	17	-	nC
$Q_{GD}$	gate-drain charge	see <u>Figure 12</u>	-	18	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 50 \text{ A}$ ; $V_{DS} = 10 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 11; see Figure 12	-	2.2	-	V
C <sub>iss</sub>	input capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	5850	-	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	1190	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	831	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 10 \text{ V}; R_L = 1 \Omega; V_{GS} = 4.5 \text{ V};$	-	34	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 4.7 \Omega; T_j = 25 °C$	-	240	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	318	-	ns
t <sub>f</sub>	fall time		-	234	-	ns
Source-d	rain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 14	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ; $V_{DS} = 20 \text{ V}$ ; $T_i = 25 \text{ °C}$	-	65	-	ns

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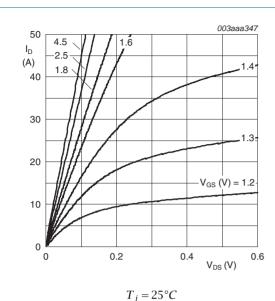
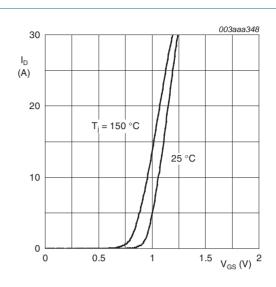
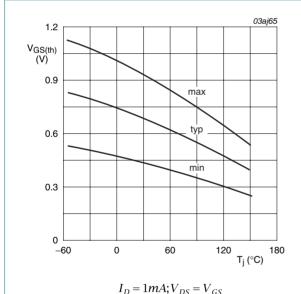


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

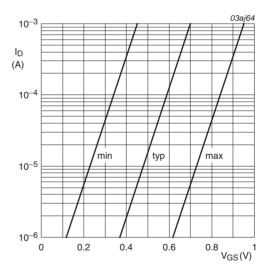


$$T_j = 25$$
°C and  $150$ °C; $V_{DS} > I_D \times R_{DSon}$ 

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



Gate-source threshold voltage as a function of Fig 7. junction temperature



 $T_i = 25^{\circ}C; V_{DS} = 5V$ 

Fig 8. Sub-threshold drain current as a function of gate-source voltage

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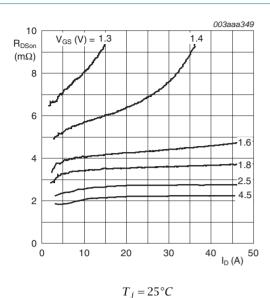


Fig 9. Drain-source on-state resistance as a function of drain current; typical values

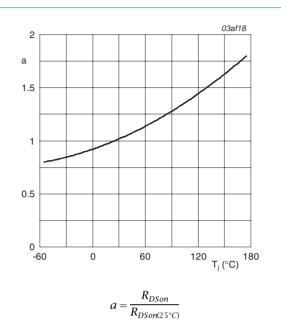
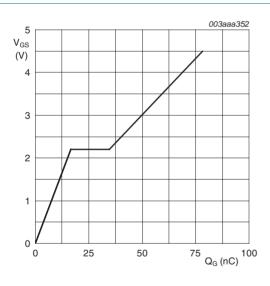
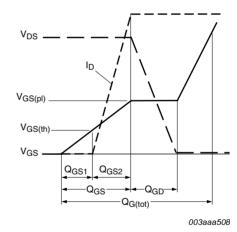


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature



 $I_D = 50A; V_{DS} = 10V$ 



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Fig 12. Gate charge waveform definitions

Fig 11. Gate-source voltage as a function of gate charge; typical values

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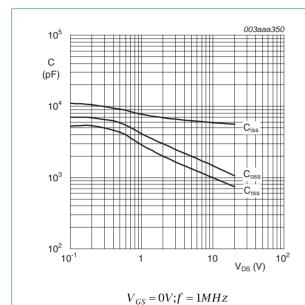


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

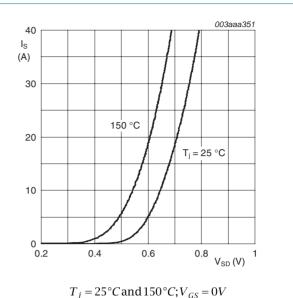


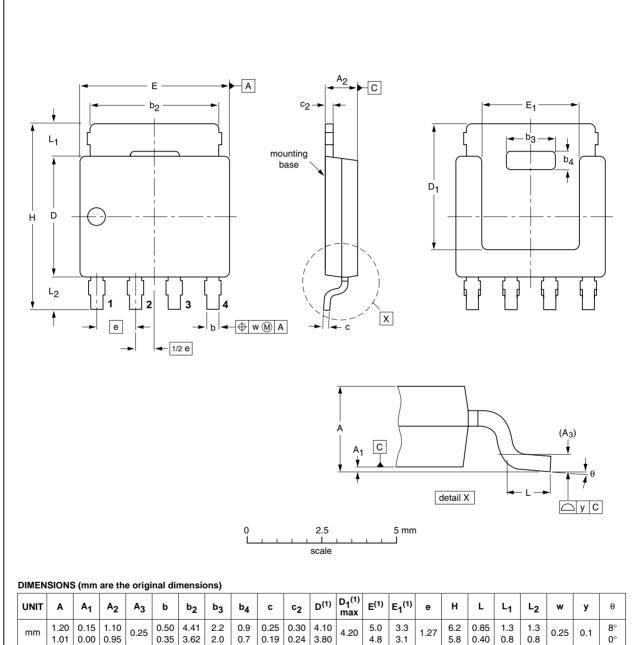
Fig 14. Source current as a function of source-drain voltage; typical values

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## **Package outline**

## Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



UNIT	Α	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b	b <sub>2</sub>	b <sub>3</sub>	b <sub>4</sub>	С	c <sub>2</sub>	D <sup>(1)</sup>	D <sub>1</sub> <sup>(1)</sup> max	E <sup>(1)</sup>	E <sub>1</sub> <sup>(1)</sup>	е	Н	L	L <sub>1</sub>	L <sub>2</sub>	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	l .	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT669		MO-235			<del>04-10-13</del> 06-03-16

Fig 15. Package outline SOT669 (LFPAK)

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## **Revision history**

#### Table 7. **Revision history**

**Product data sheet** 

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH2520U_3	20090302	Product data sheet	-	PH2520U_2
Modifications:	guidelines	of this data sheet has be of NXP Semiconductors. have been adapted to th		,
PH2520U 2	00054445	5 1 . 1 . 1 .		
F1123200_2	20051115	Product data sheet	-	PH2520U-01

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## 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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